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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Not For New Designs
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, LCD, POR, PWM, WDT
Number of I/O	51
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 20x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l100r8t6

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Table 4. Working mode-dependent functionalities (from Run/active down to standby) (continued)

Ips	Run/Active	Sleep	Low-power Run	Low-power Sleep	Stop		Standby	
						Wakeup capability		Wakeup capability
DAC	Y	Y	Y	Y	Y	-	-	-
Comparators	Y	Y	Y	Y	Y	Y	-	-
16-bit Timers	Y	Y	Y	Y	-	-	-	-
IWDG	Y	Y	Y	Y	Y	Y	Y	Y
WWDG	Y	Y	Y	Y	-	-	-	-
Systick Timer	Y	Y	Y	Y	-	-	-	-
GPIOs	Y	Y	Y	Y	Y	Y	-	2 pins
Wakeup time to Run mode	0 μ s	0.4 μ s	3 μ s	46 μ s	< 8 μ s		58 μ s	
Consumption $V_{DD}=1.8$ V to 3.6 V (Typ)	Down to 214 μ A/MHz (from Flash)	Down to 50 μ A/MHz (from Flash)	Down to 9 μ A	Down to 4.4 μ A	0.65 μ A (No RTC) $V_{DD}=1.8$ V		0.3 μ A (No RTC) $V_{DD}=1.8$ V	
					1.4 μ A (with RTC) $V_{DD}=1.8$ V		1 μ A (with RTC) $V_{DD}=1.8$ V	
					0.65 μ A (No RTC) $V_{DD}=3.0$ V		0.3 μ A (No RTC) $V_{DD}=3.0$ V	
					1.6 μ A (with RTC) $V_{DD}=3.0$ V		1.3 μ A (with RTC) $V_{DD}=3.0$ V	

1. The startup on communication line wakes the CPU which was made possible by an EXTI, this induces a delay before entering run mode.

3.2 ARM[®] Cortex[®]-M3 core with MPU

The ARM[®] Cortex[®]-M3 processor is the industry leading processor for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM[®] Cortex[®]-M3 32-bit RISC processor features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

The memory protection unit (MPU) improves system reliability by defining the memory attributes (such as read/write access permissions) for different memory regions. It provides up to eight different regions and an optional predefined background region.

Owing to its embedded ARM core, the STM32L100C6 and STM32L100R8/RB devices are compatible with all ARM tools and software.

Nested vectored interrupt controller (NVIC)

The ultra-low-power STM32L100C6 and STM32L100R8/RB devices embed a nested vectored interrupt controller able to handle up to 45 maskable interrupt channels (not including the 16 interrupt lines of Cortex-M3) and 16 priority levels.

- Closely coupled NVIC gives low-latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of *late arriving*, higher-priority interrupts
- Support for tail-chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimal interrupt latency.

3.3 Reset and supply management

3.3.1 Power supply schemes

- $V_{DD} = 1.8$ to 3.6 V: external power supply for I/Os and the internal regulator. Provided externally through V_{DD} pins.
- V_{SSA} , $V_{DDA} = 1.8$ to 3.6 V: external analog power supplies for ADC, reset blocks, RCs and PLL.
 V_{DDA} and V_{SSA} must be connected to V_{DD} and V_{SS} , respectively.

3.3.2 Power supply supervisor

The device has an integrated ZEROPOWER power-on reset (POR)/power-down reset (PDR) that can be coupled with a brownout reset (BOR) circuitry.

BOR is activated at power-on and the device operates between 1.8 V and 3.6 V.

After the V_{DD} threshold is reached, the option byte loading process starts, either to confirm or modify default thresholds, or to disable the BOR permanently.

BOR ensures proper operation starting from 1.8 V whatever the power ramp-up phase before it reaches 1.8 V.

Five BOR thresholds are available through option bytes, starting from 1.8 V to 3 V. To reduce the power consumption in Stop mode, it is possible to automatically switch off the internal reference voltage (V_{REFINT}) in Stop mode. The device remains in reset mode when V_{DD} is below a specified threshold, $V_{POR/PDR}$ or V_{BOR} , without the need for any external reset circuit.

The device features an embedded programmable voltage detector (PVD) that monitors the V_{DD}/V_{DDA} power supply and compares it to the V_{PVD} threshold. This PVD offers 7 different levels between 1.85 V and 3.05 V, chosen by software, with a step around 200 mV. An interrupt can be generated when V_{DD}/V_{DDA} drops below the V_{PVD} threshold and/or when V_{DD}/V_{DDA} is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

3.3.3 Voltage regulator

The regulator has three operation modes: main (MR), low-power (LPR) and power down.

- MR is used in Run mode (nominal regulation)
- LPR is used in the Low-power run, Low-power sleep and Stop modes
- Power down is used in Standby mode. The regulator output is high impedance, the kernel circuitry is powered down, inducing zero consumption but the contents of the registers and RAM are lost except for the standby circuitry (wake-up logic, IWDG, RTC, LSI, LSE crystal 32K osc, RCC_CSR).

3.3.4 Boot modes

At startup, boot pins are used to select one of three boot options:

- Boot from Flash memory
- Boot from System Memory
- Boot from embedded RAM

The boot loader is located in System Memory. It is used to reprogram the Flash memory by using USART1 or USART2. See the application note “STM32 microcontroller system memory boot mode” (AN2606) for details.

The HSI oscillator is to be calibrated to +/-1% before using of the bootloader.

3.14.1 General-purpose timers (TIM2, TIM3, TIM4, TIM9, TIM10 and TIM11)

There are six synchronizable general-purpose timers embedded in the STM32L100C6 and STM32L100R8/RB devices (see [Table 5](#) for differences).

TIM2, TIM3, TIM4

These timers are based on a 16-bit auto-reload up/down-counter and a 16-bit prescaler. They feature 4 independent channels each for input capture/output compare, PWM or one-pulse mode output. This gives up to 12 input captures/output compares/PWMs on the largest packages.

The TIM2, TIM3, TIM4 general-purpose timers can work together or with the TIM10, TIM11 and TIM9 general-purpose timers via the Timer Link feature for synchronization or event chaining. Their counter can be frozen in debug mode. Any of the general-purpose timers can be used to generate PWM outputs.

TIM2, TIM3, TIM4 all have independent DMA request generation.

These timers are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 3 hall-effect sensors.

TIM10, TIM11 and TIM9

TIM10 and TIM11 are based on a 16-bit auto-reload upcounter. TIM9 is based on a 16-bit auto-reload up/down counter. They include a 16-bit prescaler. TIM10 and TIM11 feature one independent channel, whereas TIM9 has two independent channels for input capture/output compare, PWM or one-pulse mode output. They can be synchronized with the TIM2, TIM3, TIM4 full-featured general-purpose timers.

They can also be used as simple time bases and be clocked by the LSE clock source (32.768 kHz) to provide time bases independent from the main CPU clock.

3.14.2 Basic timers (TIM6 and TIM7)

These timers are mainly used for DAC trigger generation. They can also be used as generic 16-bit time bases.

3.14.3 SysTick timer

This timer is dedicated to the OS, but could also be used as a standard downcounter. It is based on a 24-bit down-counter with autoreload capability and a programmable clock source. It features a maskable system interrupt generation when the counter reaches 0.

3.14.4 Independent watchdog (IWDG)

The independent watchdog is based on a 12-bit down-counter and 8-bit prescaler. It is clocked from an independent 37 kHz internal RC and, as it operates independently of the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free-running timer for application timeout management. It is hardware- or software-configurable through the option bytes. The counter can be frozen in debug mode.

6.1.6 Power supply scheme

Figure 8. Power supply scheme

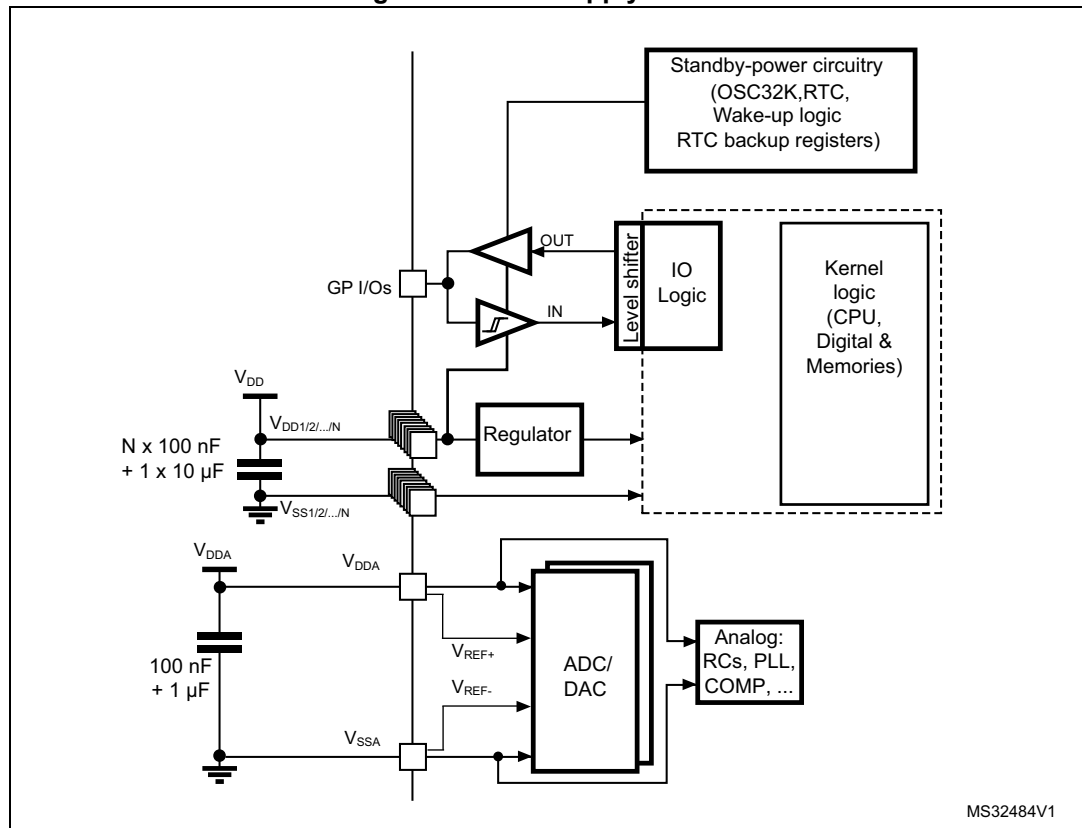


Table 11. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	-65 to +150	°C
T_J	Maximum junction temperature	105	°C
T_{LEAD}	Maximum lead temperature during soldering (LQFP64, UFQFPN48)	see note ⁽¹⁾	°C

1. Compliant with JEDEC Std J-STD-020D (for small body, Sn-Pb or Pb assembly), the ST ECOPACK[®] 7191395 specification, and the European directive on Restrictions on Hazardous Substances (ROHS directive 2011/65/EU, July 2011).

6.3 Operating conditions

6.3.1 General operating conditions

Table 12. General operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
f_{HCLK}	Internal AHB clock frequency	-	0	32	MHz
f_{PCLK1}	Internal APB1 clock frequency	-	0	32	
f_{PCLK2}	Internal APB2 clock frequency	-	0	32	
V_{DD}	Standard operating voltage	BOR detector enabled, (at power-on)	1.8	3.6	V
		BOR detector disabled, after power on	1.65	3.6	
$V_{DDA}^{(1)}$	Analog operating voltage	Must be the same voltage as $V_{DD}^{(2)}$	1.8	3.6	V
V_{IN}	I/O input voltage	FT pins: $2.0\text{ V} \leq V_{DD}$	-0.3	5.5 ⁽³⁾	V
		FT pins: $V_{DD} < 2.0\text{ V}$	-0.3	5.25 ⁽³⁾	
		BOOT0	0	5.5	
		Any other pin	-0.3	$V_{DD}+0.3$	
P_D	Power dissipation at $T_A = 85\text{ °C}^{(4)}$	LQFP64 package	-	444	mW
		UFQFPN48 package	-	606	
T_A	Ambient temperature range	Maximum power dissipation	-40	85	
T_J	Junction temperature range	$-40\text{ °C} \leq T_A \leq 85\text{ °C}$	-40	105	°C

- When the ADC is used, refer to [Table 53: ADC characteristics](#).
- It is recommended to power V_{DD} and V_{DDA} from the same source. A maximum difference of 300 mV between V_{DD} and V_{DDA} can be tolerated during power-up and operation.
- To sustain a voltage higher than $V_{DD}+0.3\text{ V}$, the internal pull-up/pull-down resistors must be disabled.
- If T_A is lower, higher P_D values are allowed as long as T_J does not exceed T_J max (see [Section 7.3: Thermal characteristics on page 97](#)).

6.3.3 Embedded internal reference voltage

The parameters given in the following table are based on characterization results, unless otherwise specified.

Table 14. Embedded internal reference voltage calibration values

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at temperature of 30 °C \pm 5 °C, $V_{DDA} = 3 \text{ V} \pm 10 \text{ mV}$	0x1FF8 0078-0x1FF8 0079

Table 15. Embedded internal reference voltage

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{\text{REFINT_out}}^{(1)}$	Internal reference voltage	$-40 \text{ }^{\circ}\text{C} < T_J < +85 \text{ }^{\circ}\text{C}$	1.202	1.224	1.242	V
I_{REFINT}	Internal reference current consumption	-	-	1.4	2.3	μA
T_{VREFINT}	Internal reference startup time	-	-	2	3	ms
$V_{\text{VREF_MEAS}}$	V_{DDA} voltage during V_{REFINT} factory measure	-	2.99	3	3.01	V
$A_{\text{VREF_MEAS}}$	Accuracy of factory-measured V_{REF} value ⁽²⁾	Including uncertainties due to ADC and V_{DDA} values	-	-	± 5	mV
$T_{\text{Ccoeff}}^{(3)}$	Temperature coefficient	$-40 \text{ }^{\circ}\text{C} < T_J < +105 \text{ }^{\circ}\text{C}$	-	25	100	ppm/ $^{\circ}\text{C}$
$A_{\text{Ccoeff}}^{(3)}$	Long-term stability	1000 hours, $T = 25 \text{ }^{\circ}\text{C}$	-	-	1000	ppm
$V_{\text{DDCcoeff}}^{(3)(4)}$	Voltage coefficient	$3.0 \text{ V} < V_{\text{DDA}} < 3.6 \text{ V}$	-	-	2000	ppm/V
$T_{\text{S_vrefint}}^{(3)}$	ADC sampling time when reading the internal reference voltage	-	4	-	-	μs
$T_{\text{ADC_BUF}}^{(3)}$	Startup time of reference voltage buffer for ADC	-	-	-	10	μs
$I_{\text{BUF_ADC}}^{(3)}$	Consumption of reference voltage buffer for ADC	-	-	13.5	25	μA
$I_{\text{VREF_OUT}}^{(3)}$	VREF_OUT output current ⁽⁵⁾	-	-	-	1	μA
$C_{\text{VREF_OUT}}^{(3)}$	VREF_OUT output load	-	-	-	50	pF
$I_{\text{LPBUF}}^{(3)}$	Consumption of reference voltage buffer for VREF_OUT and COMP	-	-	730	1200	nA
$V_{\text{REFINT_DIV1}}^{(3)}$	1/4 reference voltage	-	24	25	26	% V_{REFINT}
$V_{\text{REFINT_DIV2}}^{(3)}$	1/2 reference voltage	-	49	50	51	
$V_{\text{REFINT_DIV3}}^{(3)}$	3/4 reference voltage	-	74	75	76	

1. Guaranteed by test in production.

2. The internal V_{REF} value is individually measured in production and stored in dedicated EEPROM bytes.

3. Guaranteed by characterization results.

4. Shortest sampling time can be determined in the application by multiple interactions.

5. To guarantee less than 1% VREF_OUT deviation.

Table 16. Current consumption in Run mode, code with data processing running from Flash

Symbol	Parameter	Conditions		f _{HCLK}	Typ	Max ⁽¹⁾		Unit
						55 °C	85 °C	
I _{DD} (Run from Flash)	Supply current in Run mode, code executed from Flash	f _{HSE} = f _{HCLK} up to 16 MHz, included f _{HSE} = f _{HCLK} /2 above 16 MHz (PLL ON) ⁽²⁾	Range 3, V _{CORE} =1.2 V VOS[1:0] = 11	1 MHz	270	400	400	μA
				2 MHz	470	600	600	
				4 MHz	890	1025	1025	
			Range 2, V _{CORE} =1.5 V VOS[1:0] = 10	4 MHz	1	1.3	1.3	mA
				8 MHz	2	2.5	2.5	
				16 MHz	3.9	5	5	
			Range 1, V _{CORE} =1.8 V VOS[1:0] = 01	8 MHz	2.16	3	3	
				16 MHz	4.8	5.5	5.5	
				32 MHz	9.6	11	11	
		HSI clock source (16 MHz)	Range 2, V _{CORE} =1.5 V VOS[1:0] = 10	16 MHz	4	5	5	
			Range 1, V _{CORE} =1.8 V VOS[1:0] = 01	32 MHz	9.4	11	11	
		MSI clock, 65 kHz	Range 3, V _{CORE} =1.2 V VOS[1:0] = 11	65 kHz	0.05	0.085	0.09	
		MSI clock, 524 kHz		524 kHz	0.15	0.185	0.19	
		MSI clock, 4.2 MHz		4.2 MHz	0.9	1	1	

1. Guaranteed by characterization results, unless otherwise specified.

2. Oscillator bypassed (HSEBYP = 1 in RCC_CR register).

Table 19. Current consumption in Low power run mode

Symbol	Parameter	Conditions			Typ	Max (1)	Unit
I_{DD} (LP Run)	Supply current in Low power run mode	All peripherals OFF, code executed from RAM, Flash switched OFF, V_{DD} from 1.8 V to 3.6 V	MSI clock, 65 kHz $f_{HCLK} = 32$ kHz	$T_A = -40\text{ }^{\circ}\text{C}$ to $25\text{ }^{\circ}\text{C}$	9	12	μA
				$T_A = 85\text{ }^{\circ}\text{C}$	17.5	24	
			MSI clock, 65 kHz $f_{HCLK} = 65$ kHz	$T_A = -40\text{ }^{\circ}\text{C}$ to $25\text{ }^{\circ}\text{C}$	14	17	
				$T_A = 85\text{ }^{\circ}\text{C}$	22	29	
			MSI clock, 131 kHz $f_{HCLK} = 131$ kHz	$T_A = -40\text{ }^{\circ}\text{C}$ to $25\text{ }^{\circ}\text{C}$	37	42	
				$T_A = 55\text{ }^{\circ}\text{C}$	37	42	
				$T_A = 85\text{ }^{\circ}\text{C}$	37	42	
		All peripherals OFF, code executed from Flash, V_{DD} from 1.8 V to 3.6 V	MSI clock, 65 kHz $f_{HCLK} = 32$ kHz	$T_A = -40\text{ }^{\circ}\text{C}$ to $25\text{ }^{\circ}\text{C}$	24	32	
				$T_A = 85\text{ }^{\circ}\text{C}$	33	42	
			MSI clock, 65 kHz $f_{HCLK} = 65$ kHz	$T_A = -40\text{ }^{\circ}\text{C}$ to $25\text{ }^{\circ}\text{C}$	31	40	
				$T_A = 85\text{ }^{\circ}\text{C}$	40	48	
			MSI clock, 131 kHz $f_{HCLK} = 131$ kHz	$T_A = -40\text{ }^{\circ}\text{C}$ to $25\text{ }^{\circ}\text{C}$	48	58	
				$T_A = 55\text{ }^{\circ}\text{C}$	54	63	
				$T_A = 85\text{ }^{\circ}\text{C}$	56	65	
I_{DD} Max (LP Run) ⁽²⁾	Max allowed current in Low power run mode	V_{DD} from 1.8 V to 3.6 V	-	-	-	200	

1. Guaranteed by characterization results, unless otherwise specified.

2. This limitation is related to the consumption of the CPU core and the peripherals that are powered by the regulator. Consumption of the I/Os is not included in this limitation.

Table 21. Typical and maximum current consumptions in Stop mode (continued)

Symbol	Parameter	Conditions		Typ (1)	Max (1)(2)	Unit
I_{DD} (WU from Stop)	RMS (root mean square) supply current during wakeup time when exiting from Stop mode	MSI = 4.2 MHz	$V_{DD} = 3.0\text{ V}$ $T_A = -40^\circ\text{C to } 25^\circ\text{C}$	2	-	mA
		MSI = 1.05 MHz		1.45	-	
		MSI = 65 kHz ⁽⁶⁾		1.45	-	

1. The typical values are given for $V_{DD} = 3.0\text{ V}$ and max values are given for $V_{DD} = 3.6\text{ V}$, unless otherwise specified.
2. Guaranteed by characterization results, unless otherwise specified.
3. LCD enabled with external VLCD, static duty, division ratio = 256, all pixels active, no LCD connected.
4. LCD enabled with external VLCD, 1/8 duty, 1/3 bias, division ratio = 64, all pixels active, no LCD connected.
5. Based on characterization done with a 32.768 kHz crystal (MC306-G-06Q-32.768, manufacturer JFVNY) with two 6.8pF loading capacitors.
6. When MSI = 64 kHz, the RMS current is measured over the first 15 μs following the wakeup event. For the remaining time of the wakeup period, the current is similar to the Run mode current.

Table 22. Typical and maximum current consumptions in Standby mode

Symbol	Parameter	Conditions		Typ ⁽¹⁾	Max (1)(2)	Unit
I_{DD} (Standby with RTC)	Supply current in Standby mode with RTC enabled	RTC clocked by LSI (no independent watchdog)	$T_A = -40^\circ\text{C to } 25^\circ\text{C}$ $V_{DD} = 1.8\text{ V}$	0.9	-	μA
			$T_A = -40^\circ\text{C to } 25^\circ\text{C}$	1.1	1.8	
			$T_A = 55^\circ\text{C}$	1.42	2.5	
			$T_A = 85^\circ\text{C}$	1.87	3	
		RTC clocked by LSE (no independent watchdog) ⁽³⁾	$T_A = -40^\circ\text{C to } 25^\circ\text{C}$ $V_{DD} = 1.8\text{ V}$	1	-	
			$T_A = -40^\circ\text{C to } 25^\circ\text{C}$	1.33	2.9	
			$T_A = 55^\circ\text{C}$	1.59	3.4	
			$T_A = 85^\circ\text{C}$	2.01	4.3	
I_{DD} (Standby)	Supply current in Standby mode with RTC disabled	Independent watchdog and LSI enabled	$T_A = -40^\circ\text{C to } 25^\circ\text{C}$	1.1	1.6	μA
			$T_A = -40^\circ\text{C to } 25^\circ\text{C}$	0.3	0.55	
		Independent watchdog and LSI OFF	$T_A = 55^\circ\text{C}$	0.5	0.8	
			$T_A = 85^\circ\text{C}$	1	1.7	
I_{DD} (WU from Standby)	RMS supply current during wakeup time when exiting from Standby mode	-	$V_{DD} = 3.0\text{ V}$ $T_A = -40^\circ\text{C to } 25^\circ\text{C}$	1	-	mA

1. The typical values are given for $V_{DD} = 3.0\text{ V}$ and max values are given for $V_{DD} = 3.6\text{ V}$, unless otherwise specified.
2. Guaranteed by characterization results, unless otherwise specified.
3. Based on characterization done with a 32.768 kHz crystal (MC306-G-06Q-32.768, manufacturer JFVNY) with two 6.8pF loading capacitors.

On-chip peripheral current consumption

The current consumption of the on-chip peripherals is given in the following table. The MCU is placed under the following conditions:

- all I/O pins are in input mode with a static value at V_{DD} or V_{SS} (no load)
- all peripherals are disabled unless otherwise mentioned
- the given value is calculated by measuring the current consumption
 - with all peripherals clocked off
 - with only one peripheral clocked on

Table 23. Peripheral current consumption⁽¹⁾

Peripheral		Typical consumption, $V_{DD} = 3.0\text{ V}$, $T_A = 25\text{ °C}$				Unit
		Range 1, $V_{CORE}=1.8\text{ V}$ $VOS[1:0] = 01$	Range 2, $V_{CORE}=1.5\text{ V}$ $VOS[1:0] = 10$	Range 3, $V_{CORE}=1.2\text{ V}$ $VOS[1:0] = 11$	Low power sleep and run	
APB1	TIM2	13	10.5	8	10.5	$\mu\text{A/MHz}$ (f_{HCLK})
	TIM3	14	12	9	12	
	TIM4	12.5	10.5	8	11	
	TIM6	5.5	4.5	3.5	4.5	
	TIM7	5.5	5	3.5	4.5	
	LCD	5.5	5	3.5	5	
	WWDG	4	3.5	2.5	3.5	
	SPI2	5.5	5	4	5	
	USART2	9	8	5.5	8.5	
	USART3	10.5	9	6	8	
	I2C1	8.5	7	5.5	7.5	
	I2C2	8.5	7	5.5	6.5	
	USB	12.5	10	6.5	10	
	PWR	4.5	4	3	3.5	
	DAC	9	7.5	6	7	
	COMP	4.5	4	3.5	4.5	
APB2	SYSCFG & RI	3	2.5	2	2.5	$\mu\text{A/MHz}$ (f_{HCLK})
	TIM9	9	7.5	6	7	
	TIM10	6.5	5.5	4.5	5.5	
	TIM11	7	6	4.5	5.5	
	ADC ⁽²⁾	11.5	9.5	8	9	
	SPI1	5	4.5	3	4	
	USART1	9	7.5	6	7.5	

Note: For CL1 and CL2, it is recommended to use high-quality ceramic capacitors in the 5 pF to 15 pF range selected to match the requirements of the crystal or resonator (see [Figure 14](#)). CL1 and CL2, are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of CL1 and CL2.

Load capacitance CL has the following formula: $CL = CL1 \times CL2 / (CL1 + CL2) + C_{stray}$ where C_{stray} is the pin capacitance and board or trace PCB-related capacitance. Typically, it is between 2 pF and 7 pF.

Caution: To avoid exceeding the maximum value of CL1 and CL2 (15 pF) it is strongly recommended to use a resonator with a load capacitance $CL \leq 7$ pF. Never use a resonator with a load capacitance of 12.5 pF.

Example: if you choose a resonator with a load capacitance of $CL = 6$ pF and $C_{stray} = 2$ pF, then $CL1 = CL2 = 8$ pF.

Figure 14. Typical application with a 32.768 kHz crystal

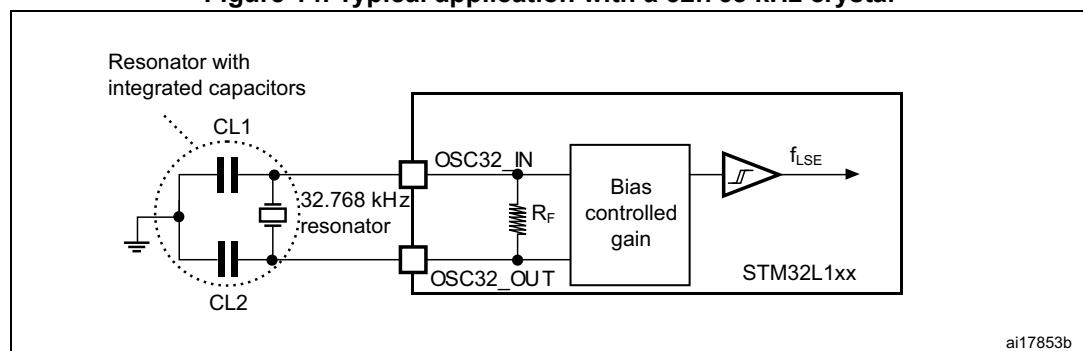
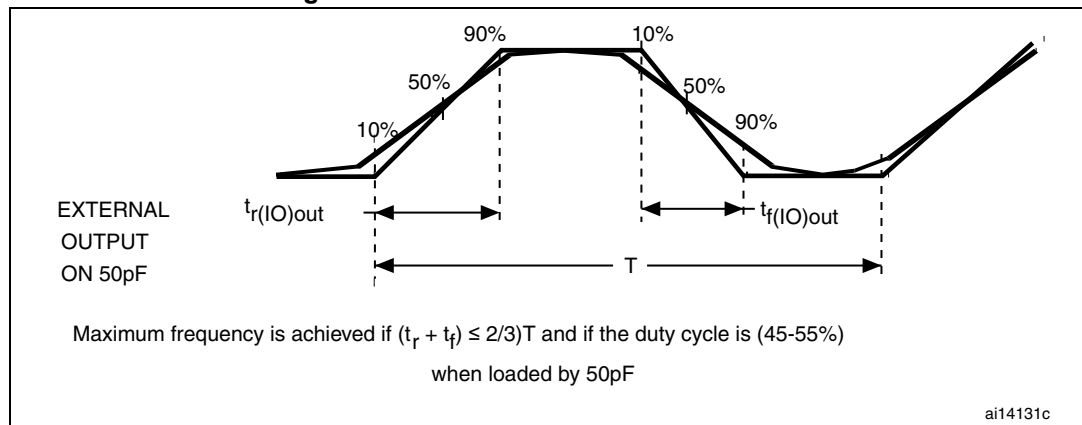


Figure 15. I/O AC characteristics definition



6.3.14 NRST pin characteristics

The NRST pin input driver uses CMOS technology. It is connected to a permanent pull-up resistor, RPU (see [Table 44](#)).

Unless otherwise specified, the parameters given in [Table 44](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 12](#).

Table 44. NRST pin characteristics

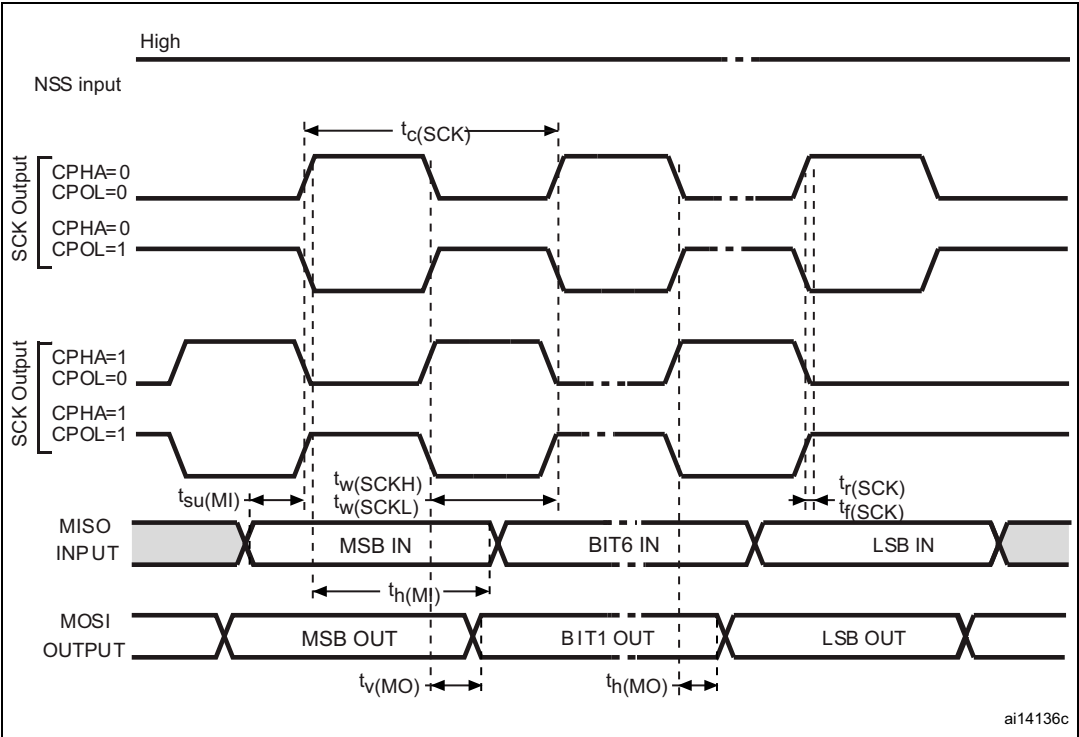
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NRST)}^{(1)}$	NRST input low level voltage	-	-	-	$0.3 V_{DD}$	V
$V_{IH(NRST)}^{(1)}$	NRST input high level voltage	-	$0.39 V_{DD}+0.59$	-		
$V_{OL(NRST)}^{(1)}$	NRST output low level voltage	$I_{OL} = 2 \text{ mA}$ $2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	-	-	0.4	
		$I_{OL} = 1.5 \text{ mA}$ $1.8 \text{ V} < V_{DD} < 2.7 \text{ V}$	-	-		
$V_{hys(NRST)}^{(1)}$	NRST Schmitt trigger voltage hysteresis	-	-	$10\%V_{DD}^{(2)}$		mV
R_{PU}	Weak pull-up equivalent resistor ⁽³⁾	$V_{IN} = V_{SS}$	30	45	60	kΩ
$V_F(NRST)^{(1)}$	NRST input filtered pulse	-	-	-	50	ns
$V_{NF(NRST)}^{(1)}$	NRST input not filtered pulse	-	350	-	-	ns

1. Guaranteed by design.

2. 200 mV minimum value

3. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is around 10%.

Figure 20. SPI timing diagram - master mode⁽¹⁾



1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

USB characteristics

The USB interface is USB-IF certified (full speed).

Table 49. USB startup time

Symbol	Parameter	Max	Unit
$t_{STARTUP}^{(1)}$	USB transceiver startup time	1	μs

1. Guaranteed by design.

6.3.20 LCD controller

The STM32L100C6 and STM32L100R8/RB devices embed a built-in step-up converter to provide a constant LCD reference voltage independently from the V_{DD} voltage. An external capacitor C_{ext} must be connected to the V_{LCD} pin to decouple this converter.

Table 59. LCD controller characteristics

Symbol	Parameter	Min	Typ	Max	Unit
V_{LCD}	LCD external voltage	-	-	3.6	V
V_{LCD0}	LCD internal reference voltage 0	-	2.6	-	
V_{LCD1}	LCD internal reference voltage 1	-	2.73	-	
V_{LCD2}	LCD internal reference voltage 2	-	2.86	-	
V_{LCD3}	LCD internal reference voltage 3	-	2.98	-	
V_{LCD4}	LCD internal reference voltage 4	-	3.12	-	
V_{LCD5}	LCD internal reference voltage 5	-	3.26	-	
V_{LCD6}	LCD internal reference voltage 6	-	3.4	-	
V_{LCD7}	LCD internal reference voltage 7	-	3.55	-	
C_{ext}	V_{LCD} external capacitance	0.1	-	2	μF
$I_{LCD}^{(1)}$	Supply current at $V_{DD} = 2.2 V$	-	3.3	-	μA
	Supply current at $V_{DD} = 3.0 V$	-	3.1	-	
$R_{Htot}^{(2)}$	Low drive resistive network overall value	5.28	6.6	7.92	$M\Omega$
$R_L^{(2)}$	High drive resistive network total value	192	240	288	$k\Omega$
V_{44}	Segment/Common highest level voltage	-	-	V_{LCD}	V
V_{34}	Segment/Common 3/4 level voltage	-	$3/4 V_{LCD}$	-	V
V_{23}	Segment/Common 2/3 level voltage	-	$2/3 V_{LCD}$	-	
V_{12}	Segment/Common 1/2 level voltage	-	$1/2 V_{LCD}$	-	
V_{13}	Segment/Common 1/3 level voltage	-	$1/3 V_{LCD}$	-	
V_{14}	Segment/Common 1/4 level voltage	-	$1/4 V_{LCD}$	-	
V_0	Segment/Common lowest level voltage	0	-	-	
$\Delta V_{xx}^{(2)}$	Segment/Common level voltage error $T_A = -40$ to $85^\circ C$	-	-	± 50	mV

1. LCD enabled with 3 V internal step-up active, 1/8 duty, 1/4 bias, division ratio= 64, all pixels active, no LCD connected

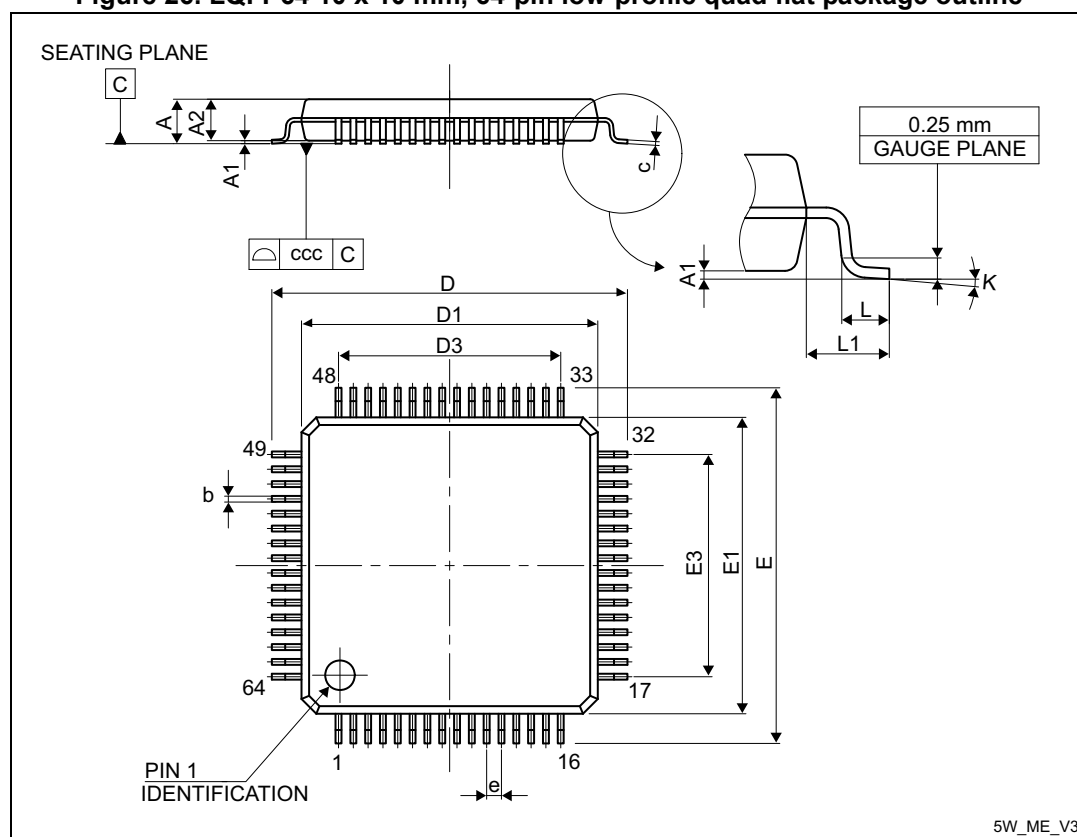
2. Guaranteed by characterization results.

7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.

7.1 LQFP64 10 x 10 mm, 64-pin low-profile quad flat package information

Figure 26. LQFP64 10 x 10 mm, 64-pin low-profile quad flat package outline



1. Drawing is not to scale.

Table 60. LQFP64 10 x 10 mm, 64-pin low-profile quad flat package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Typ	Min	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571

7.3.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from www.jedec.org.